Atomic-volume deviations and occurrence of semiconducting properties in transition metal sulphides

While all the sulphides of non-transition elements are semiconductors [1], many sulphides of transition metals are metals. The aim of the present note is to consider the relationship between the occurence of semiconducting properties and the deviations of atomic volume from additivity in the sulphides of transition metals having three-dimensional networks of metal atoms. The compounds Mo_6S_8 [2] and Nb_3S_4 [3] and the disulphides ZrS₂, NbS₂, MoS₂, etc. [4], since they are built up of clusters of atoms or of layers or having large holes, are omitted from consideration. The percentage deviation of the atomic volume, V, from the sum of its components, $\Sigma\Omega$, is given by

$$K = \frac{m+n}{2n} \frac{\Sigma \Omega - V}{V} 100 = \alpha \frac{\Delta V}{V}, \quad (1)$$

where ΔV is given by $\Sigma \Omega - V$, α is equal to 100[(m+n)/2n], and m and n are the numbers of atoms of transition metal, \mathcal{T} , and of sulphur, S in the compound $\mathcal{T}_m S_n$, respectively. The coefficient (m+n)/2n provides the normalization to the case of equiatomic compounds, $\mathcal{T}S$, since the contraction of the compound is due mainly to the presence of the sulphur atoms. Information on the type of conductivity was taken mainly from the available reviews [3,5,6] and from data on atomic

TABLE I Sulphides of non-magnetic transition metals (with the exception of Rn, Os, Rn, Os, Rh and Ir sulphides)

Compound	Structure	$\alpha \frac{\Delta V}{V}$	Type of conductor	Т _с (К)	Compound	Structure	$\alpha \frac{\Delta V}{V}$	Type of conductor	Т _с (К)
$La_{5}S_{7}$	tetragonal	4	_	_	LaS	NaC1	24	metallic	0.84
$\operatorname{Re}_{2}S_{7}$	tetragonal	5	semiconducting		$Pd_{16}S_7$	cubic	25	_	_
VS_4	monoclinic	6	semiconducting		La₃S₄	Th ₃ P ₄	25	metallic	8.1
Zr ₉ S ₂	tetragonal	8		_	Ta_2S	orthorhombic	27	metallic	
Hf_2S_3	CdI ₂	8	semiconducting	-	V ₅ S ₄	Ti₅Te₄	28	metallic	
PtS	tetragonal	10	semiconducting	_	Ti₃S₄	rhombic	28	metallic	
$Hf_{3}S_{4}$	monoclinic	11	semiconducting	_	Pd₃S	orthorhombic	29	metallic	_
PdS ₂	orthorhombic	12	semiconducting		Ti₄S₅	Ti₄S₅	30	metallic	
Lu ₂ S ₃	hexagonal	12	semiconducting	_	V ₃ S ₄	monoclinic	30	metallic	_
V_7S_8	orthorhombic	13	_	_	Hf_2S	Hf₂S	31	metallic	_
ZrS ₃	monoclinic	14	semiconducting	_	VS _{0.9}	orthorhombic	31		_
La_2S_3	Cd_2S_3	14	semiconducting	< 1.3	Ta ₆ S	monoclinic	33	_	
Sc_2S_3	orthorhombic	14	semiconducting		Y ₄ S ₃	NaC1	34	metallic	_
HfS ₃	ZrSe ₃	14	semiconducting		Nb _{0.9} S	NiAs	34	metallic	—
Mo ₂ S ₃	monoclinic	14		_	ZrS	NaC1	35	metallic	4.0
TaS ₃	orthorhombic	15	semiconducting	_	TiS	NiAs	37	metallic	< 1.0
PtS ₂	CdI ₂	16	semiconducting	_	NbS	MnP	39	metallic	< 1.3
NbS ₃	monoclinic	16	semiconducting		VS	MnP	39	metallic	
Y_2S_3	monoclinic	17	semiconducting	—	ScS	NaCl	39	metallic	< 0.3
PdS	tetragonal	17	semiconducting	< 0.3	Pd₄S	Pd₄Se	39	metallic	< 0.3
La_2S_3	Ce_2S_3	17	semiconducting	-	Nb ₂₁ S ₈	tetragonal	4 1	metallic	-
Zr ₃ S ₄	cubic	19		-	HfS	WC	41	metallic	_
TiS 3	monoclinic	19	semiconducting		YS	NaC1	42	metallic	1.9
$Hf_{3}S_{4}$	cubic	20	-		TiS _{0.5}	WC	42	metallic	_
LaS_2	orthorhombic	21	semiconducting		Ti ₃ S ₄	monoclinic	43	metallic	
					ZrS _{0.5}	WC	43	metallic	_
Pd 2.2S	cubic	21	metallic	1.6	Nb₁₄S₅	orthorhombic	43	metallic	
La_2S_4	cubic	21	-		V ₃ S	tetragonal	46	metallic	< 1.1
Ti₅S ₈	rhombic	21	metallic	*****	LuS	NaC1	46	metallic	1.0
ZrS	CuTi	22	-		V ₃ S	tetragonal	47	metallic	
Y ₅ S ₇	monoclinic	23	metallic	_	Ti ₈ S ₃	monoclinic	52		_
V_5S_8	monoclinic	23	metallic	_	Ti ₂ S	Ta₂S	47	metallic	_
Ti ₈ S ₁₂	rhombic	24	metallic	-	Zr ₂ S	Ta ₂ S	59	metallic	****

volumes. Critical temperature, T_c , values were taken from [7, 8]. For the atomic volume of sulphur a value of 25.52 Å³ was adopted.

Table I shows that metallic properties (apart from the case of pnictides [8]) are associated with a large atomic volume contraction ($K \ge 21$), while semiconducting properties are associated with a small atomic volume contraction ($K \leq 21$). There are however some exceptions to this rule, which are related to the position of the given transition metal in the Periodic Table. For instance, such violations appear for sulphides of metals with 6 (Cr, U), 8 (Ru, Os) and 9 (Rh, Ir) outer electrons. While metallic compounds $Rh_{17}S_{15}$ (K = 28, $T_{\rm c} = 5.8 \,\text{K}$) and IrS_2 (FeS₂ structure, K = 31) obey the rule, the semiconducting compounds IrS_2 ($IrSe_2$ structure. K = 24), Ir_2S_3 (*K* = 28), Rh_2S_3 (K = 28), RuS₂ $(K = 35, T_c < 0.3 \text{ K})$ and OsS₂ (K = 35) violate the rule. Since these compounds are difficult to prepare stoichiometrically [10], they are insufficiently investigated [3]. One explanation of these exceptions to the rule is that the compounds are in fact metallic, and that the semiconducting behaviour is due to the precipitation of thin layers of sulphur on the grain boundaries. An alternative explanation is based on the possibility that in these compounds the valency of (and therefore the number of electrons provided for bonding by) sulphur atoms is higher than usual (see [1]). Other deviations from the rule are observed in chromium (for non-magnetic chromium $V = 11.9 \text{ Å}^3 [11]$) and uranium sulphides having atomic magnetic moments and forming metallic compounds; for instance, for Cr_3S_4 , K = 16; for Cr₅S₆, K = 18; for US, K = 7; and for U_3S_5 , K = 7. These anomalies could be explained by taking into consideration that, for example, in US (magnetic moment per U atom, p, equals $1.7 \,\mu\text{B}$ [12]), the number of U-atom electrons, \bar{n}_{k} , involved in bounding, is 4.3 [13, 14], while for metallic U, $\bar{n}_{k} = 6$. Therefore, in calculating \overline{K} for US the value of atomic volume, V, for U ought to be found by interpolation between atomic volumes of Th and Pa, corresponding to the average number of valence electrons 4.3 (i.e. $V = 30.4 \text{ Å}^3$), leading, for the metallic US, to the value $\overline{K} = 36$ in agreement with the rule. It should be noted, however, that the value for atomic magnetic moment should be calculated from the saturation magnetization for ferromagnetics, which can sometines differ from data from neutron measurements [12].

It is interesting in this connection to also consider transition metal compounds of other classes: aluminides, silicides and oxides.

The case of the antiferromagnetic alloy Cr₃Al $(p = 1.07 \,\mu\text{B}, \,\overline{K} = 13)$ has been discussed already in the previous note [15]. In silicides, apart from ReSi₂ [15], an anomalous, large value of K is observed in the non-magnetic compound CrSi₂ (K = 33), reported as being semiconducting in a series of papers [16]. In spite of these data it is still possible that the intrinsic properties of this compound are metallic, but that the semiconducting behaviour is caused by the precipitation of very thin layers of Si or SiO₂ on the grain boundaries. This supposition is supported by the fact that in some samples with metallic lustre the resistivity, ρ , was found to be very small ($\rho =$ $7\mu\Omega$ cm) [14]. Moreover, the dependence of both resistivity and thermoelectric power on composition shows a sharp minimum corresponding to the compound CrSi2 which is characteristic for metallic compounds, but not for semiconducting compounds [17].

The very small change of atomic volume in the metal-semiconductor transition in VO_2 [18] is inconsistent with the point of view considered above. However this could be explained by the assumption that in metallic state the oxygen valency (and the number of bonding electrons provided by oxygen atoms) is 2, while in the semiconducting state oxygen atoms display valency of 4, leading to the additional contraction and compensating for the expansion that is characteristic to the semiconducting state.

It seems, therefore, that in the compound of given composition the atomic volume of the semiconducting state is bigger than that in the metallic state, provided that the valences of the components and the total number of bonding electrons are the same.

Anomalous increases (by three orders of magnitude) in the resistivity of polycrystals compared with that of the single crystals has been found in Sm-doped barium titanate [19]. The increase was attributed to the grain boundary effect. Small single crystals of $CrSi_2$, having a size of about 1 mm³, have been produced by means of chemical transport reaction [20], but the electrical properties of these crystals have not been investigated. The specimens prepared by sintering [21] and by the floating zone technique [22] show a decrease in their resistivity with temperature from 660K to the lower temperature and an increase in resistivity (up to three orders of magnitude) due to doping with a small amount of Mn, which is characteristic of metallic rather than semiconducting compounds. Although the author of the work [22] assumes that the specimens prepared by zone-melting are single crystals, no detailed metallographic and X-ray investigations, confirming this supposition, were mentioned. Detailed characterization is necessary since the crystallization of compounds with high melting points infrequently produces many blocks of size over 1 mm. As a result such specimens also show regular Laue patterns characteristic of a single crystal (the dimension of the X-ray beam is about 1 mm²) in spite of the presence of grain boundaries.

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